Mechanisms Underlying Memory Distortion for Emotional Orthographic Associates with EEG Nicholas R. Griffin, David M. Schnyer The University of Texas at Austin

- lures in MDD participants than controls³.
- isolate false alarms to emotive critical lures⁴ (Fig 2).
- - dependent (depressive symptom driven).

- \geq 16 = High CESD group (max = 60). Low CESD: n = 30. High: n = 30.





- effortful endorsements of test items.

calibration for correct responses at test than the Low CESD group.

Confidence tracked memory accuracy better for High CESD group, suggesting more

Behavior in Exp. 2 was more strongly predicted by Negative Affect than CESD, indicating that testing differences may be more trait- than state-dependent.

• Preliminary ERP evidence suggests Negative Affect may be associated with shift in

strategy toward post-retrieval monitoring; different item types may lead to

relatively similar ERP response as mood state becomes more extreme.